

RoHS Compliant Product
A suffix of "-C" specifies halogen free

DESCRIPTION

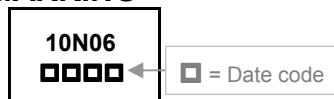
SSG10N06-C is the highest performance trench N-ch MOSFETs with extreme high cell density, which provides excellent $R_{DS(ON)}$ and gate charge for most of the synchronous buck converter applications.

SSG10N06-C meets the RoHS and Green Product requirement with full function reliability approved.

FEATURES

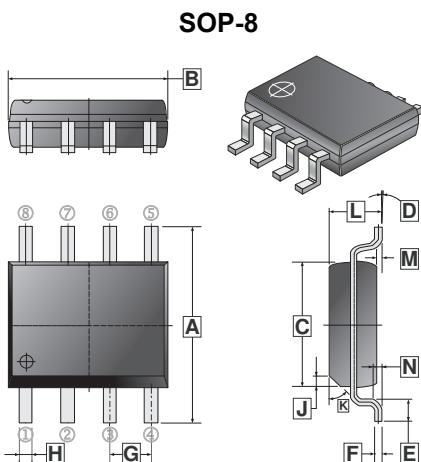
- Advanced high cell density Trench technology
- Excellent Cdv/dt effect decline
- Green device available
- Super low gate charge

MARKING



PACKAGE INFORMATION

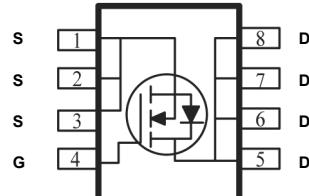
Package	MPQ	Leader Size
SOP-8	2.5K	13 inch



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.79	6.20	H	0.33	0.51
B	4.70	5.11	J	0.375	REF.
C	3.80	4.00	K	45°	REF.
D	0°	8°	L	1.3	1.752
E	0.40	1.27	M	0	0.25
F	0.10	0.25	N	0.25	REF.
G	1.27	TYP.			

ORDER INFORMATION

Part Number	Type
SSG10N06-C	Lead (Pb)-free and Halogen-free



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	±20	V
Continuous Drain Current@ $V_{GS}=10V$ ¹	I_D	10	A
		8.5	
Pulsed Drain Current ²	I_{DM}	40	A
Power Dissipation ³	P_D	1.5	W
Maximum Thermal Resistance from Junction to Ambient ¹	$R_{\theta JA}$	80	°C/W
Maximum Thermal Resistance from Junction to Case ¹	$R_{\theta JC}$	24	°C/W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55~150	°C

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Drain-Source Breakdown Voltage	BV_{DSS}	60	-	-	V	$\text{V}_{\text{GS}}=0$, $I_D=250\mu\text{A}$
Gate-Threshold Voltage	$\text{V}_{\text{GS(th)}}$	1.2	-	2.5	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}$, $I_D=250\mu\text{A}$
Forward Transconductance	g_{fs}	-	48	-	S	$\text{V}_{\text{DS}}=5\text{V}$, $I_D=10\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$\text{V}_{\text{DS}}=0\text{V}$, $\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current	$\text{T}_J=25^\circ\text{C}$ $\text{T}_J=55^\circ\text{C}$	I_{DSS}	-	-	1	$\text{V}_{\text{DS}}=48\text{V}$, $\text{V}_{\text{GS}}=0$
			-	-	5	
Static Drain-Source On-Resistance ²	$\text{R}_{\text{DS(ON)}}$	-	-	12	mΩ	$\text{V}_{\text{GS}}=10\text{V}$, $I_D=10\text{A}$
		-	-	15		$\text{V}_{\text{GS}}=4.5\text{V}$, $I_D=6\text{A}$
Total Gate Charge	Q_g	-	28.7	-	nC	$\text{V}_{\text{DS}}=48\text{V}$ $\text{V}_{\text{GS}}=4.5\text{V}$ $I_D=10\text{A}$
Gate-Source Charge	Q_{gs}	-	10.5	-		
Gate-Drain ("Miller") Charge	Q_{gd}	-	9.9	-		
Turn-on Delay Time	$\text{T}_{\text{d(on)}}$	-	10.4	-	nS	$\text{V}_{\text{DD}}=30\text{V}$ $\text{V}_{\text{GS}}=10\text{V}$ $\text{R}_G=3.3\Omega$ $I_D=10\text{A}$
Rise Time	T_r	-	9.2	-		
Turn-off Delay Time	$\text{T}_{\text{d(off)}}$	-	63	-		
Fall Time	T_f	-	4.8	-		
Input Capacitance	C_{iss}	-	3240	-	pF	$\text{V}_{\text{DS}}=15\text{V}$ $\text{V}_{\text{GS}}=0$ $f=1\text{MHz}$
Output Capacitance	C_{oss}	-	210	-		
Reverse Transfer Capacitance	C_{rss}	-	146	-		

Source-Drain Diode Characteristics

Diode Forward Voltage ²	V_{SD}	-	-	1.2	V	$I_s=1\text{A}$, $\text{V}_{\text{GS}}=0$
Continuous Source Current ^{1,4}	I_s	-	-	10	A	$\text{V}_G=\text{V}_D=0\text{V}$, Force Current
Pulsed Source Current ^{2,4}	I_{SM}	-	-	40	A	
Reverse Recovery Time	t_{rr}	-	18	-	nS	$I_F=10\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$
Reverse Recovery Charge	Q_{rr}	-	15.6	-	nC	

Notes:

1. The data is tested with the surface of the device mounted on a 1 inch² FR4 board with 2OZ copper.
2. The data is tested by pulse: pulse width≤300μs, duty cycle ≤2%
3. The power dissipation is limited by 150°C junction temperature.
4. The data is theoretically the same as I_D and I_{DM} ; in real applications, it should be limited by the total power dissipation.

CHARACTERISTIC CURVE

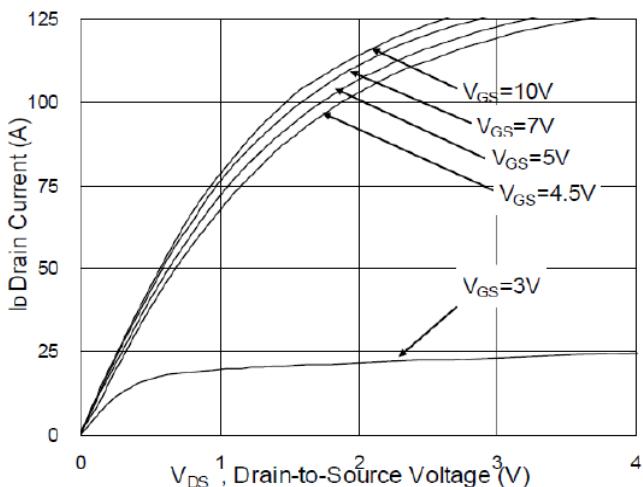


Fig.1 Typical Output Characteristics

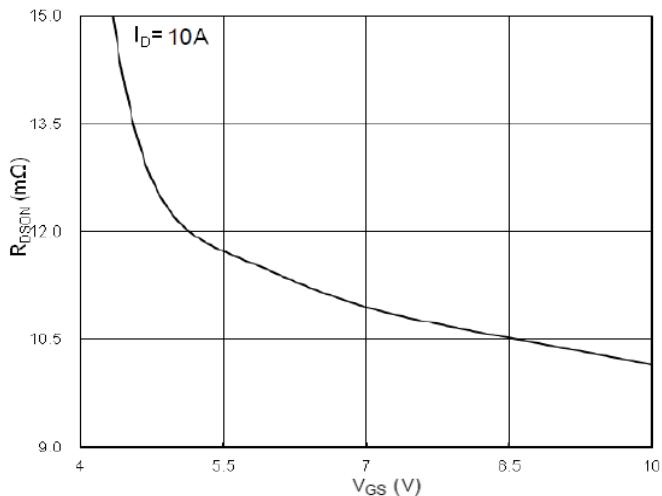


Fig.2 On-Resistance v.s Gate-Source

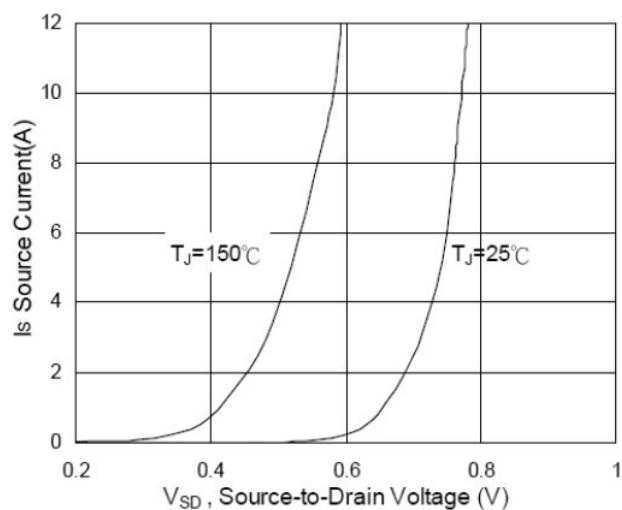


Fig.3 Forward Characteristics of Reverse

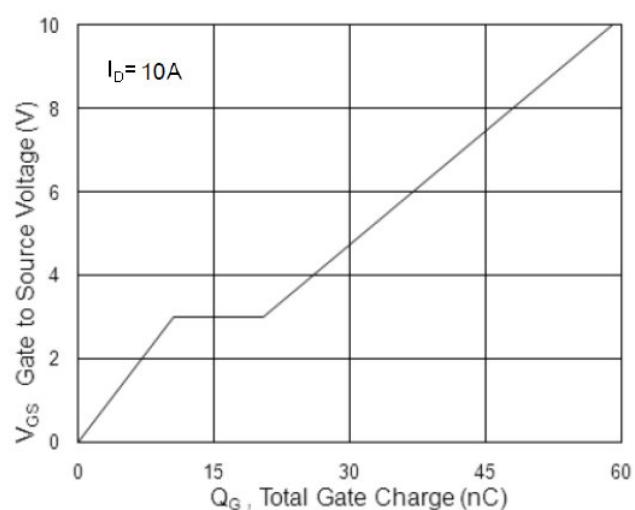


Fig.4 Gate-Charge Characteristics

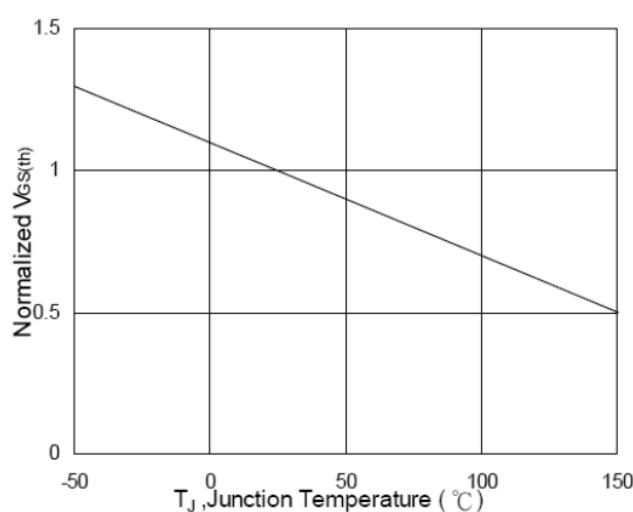


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

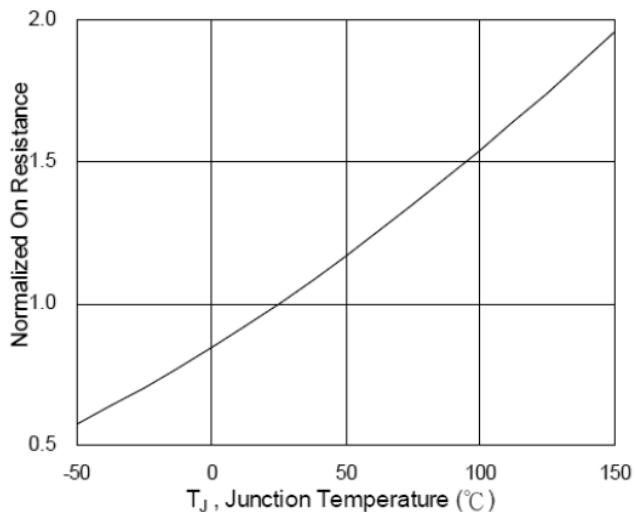


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

CHARACTERISTIC CURVE

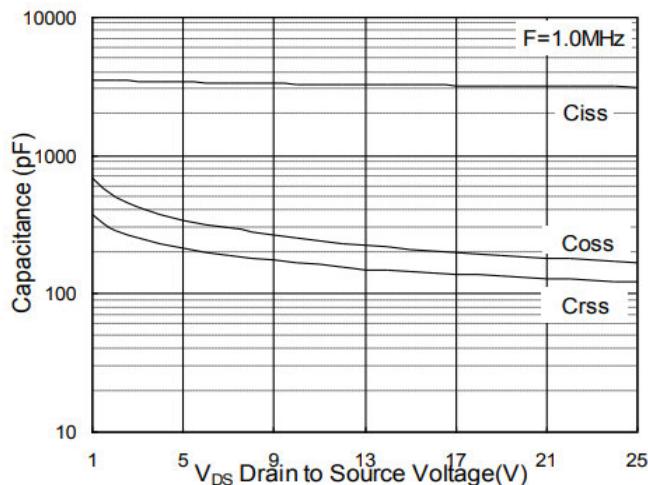


Fig.7 Capacitance

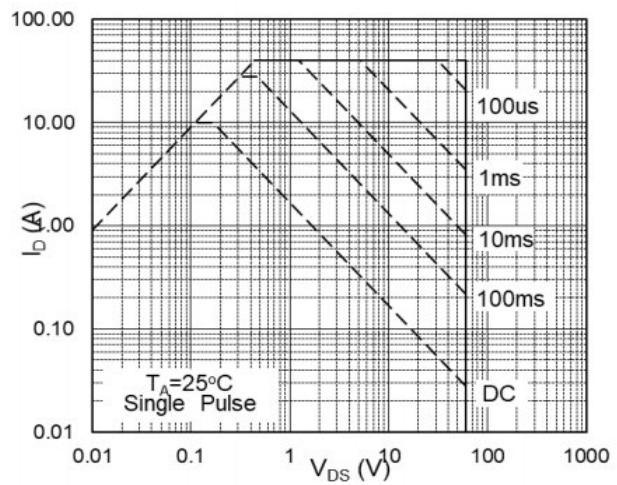


Fig.8 Safe Operating Area

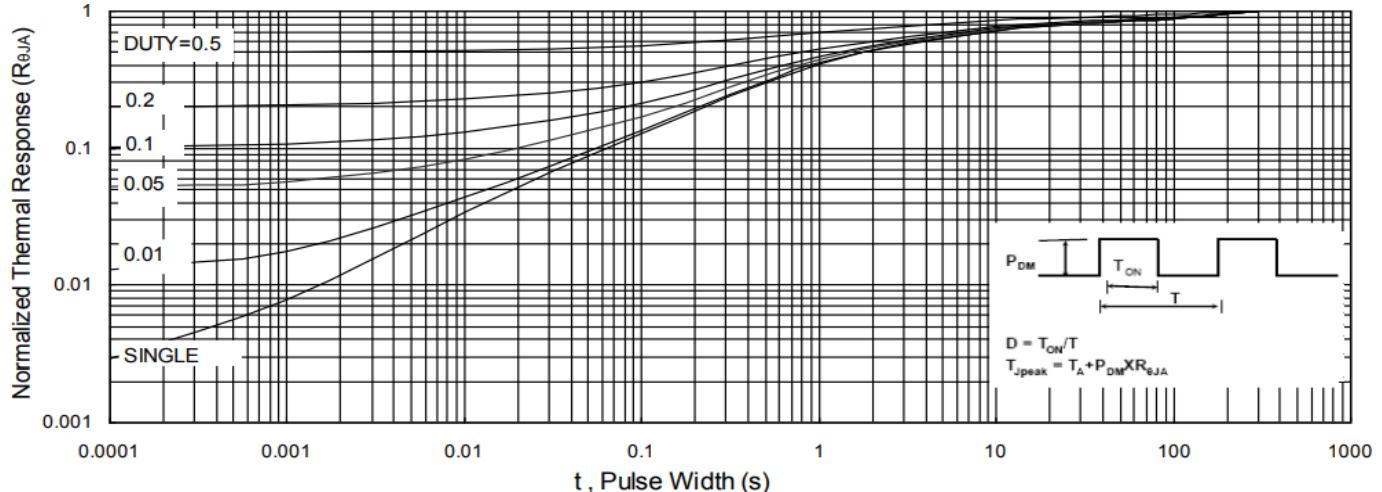


Fig.9 Normalized Maximum Transient Thermal Impedance

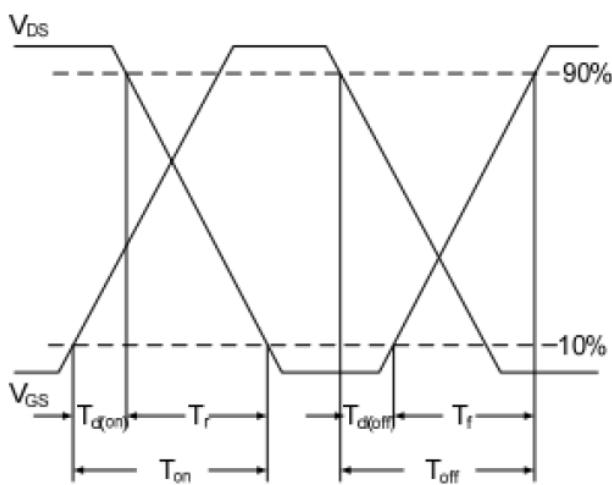


Fig.10 Switching Time Waveform

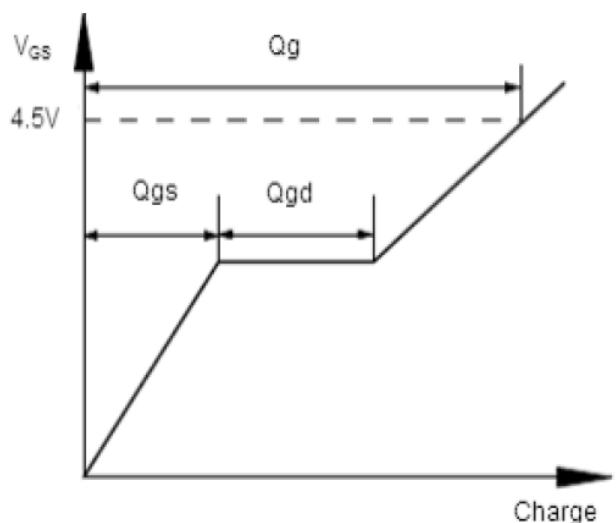


Fig.11 Gate Charge Waveform